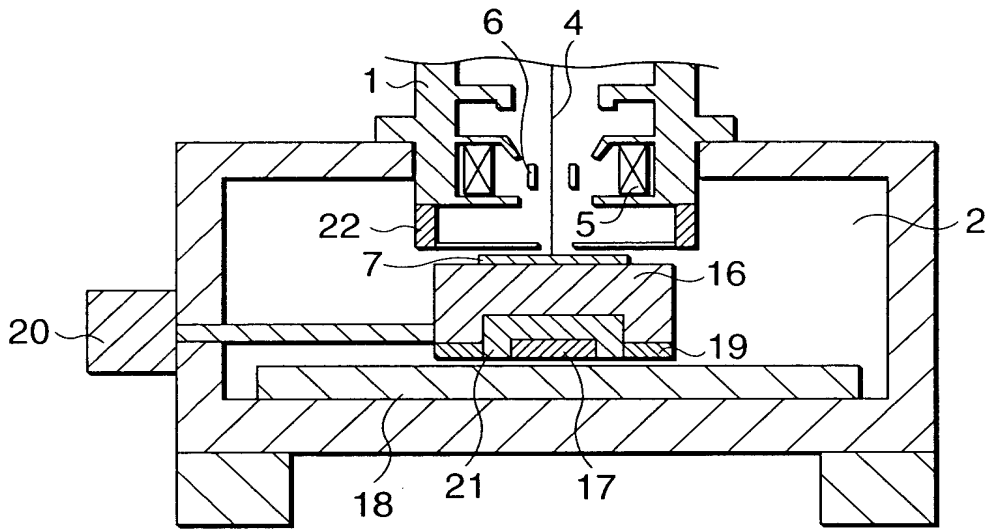
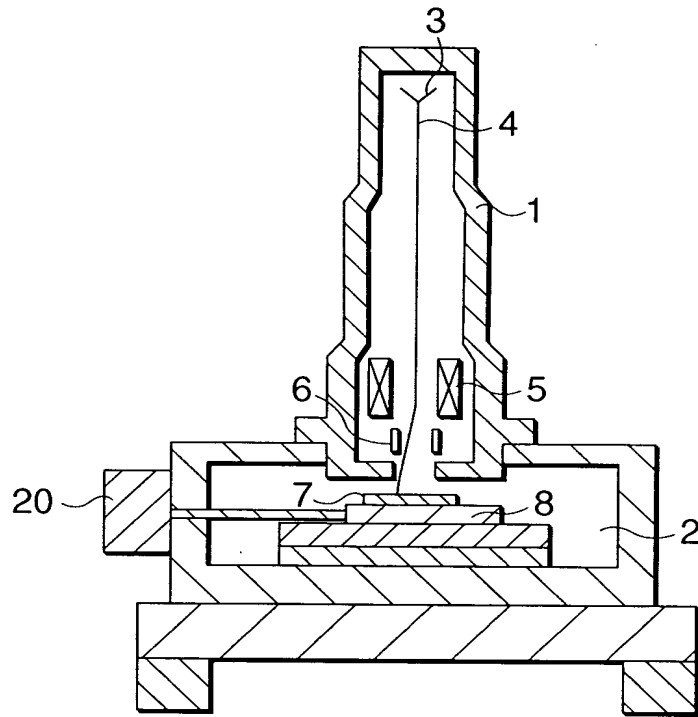


FIG. 1



09691234-101900

FIG. 2



006707-4E2F6960

FIG. 3A

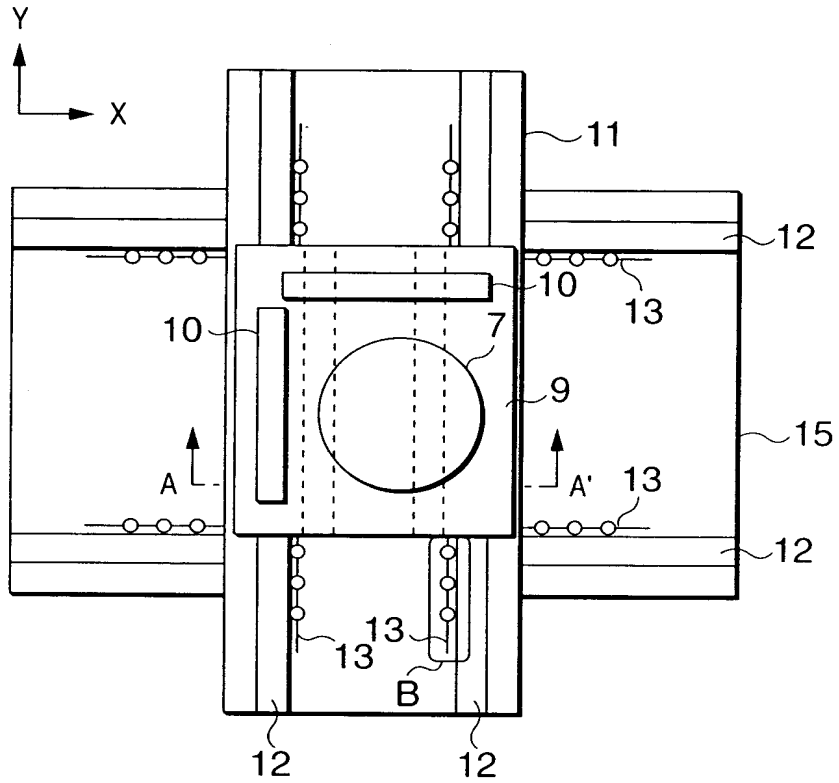
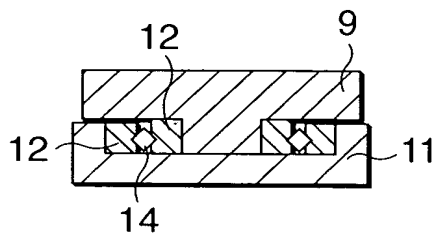
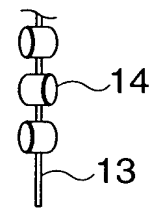


FIG. 3B



SECTIONAL VIEW TAKEN  
ALONG LINE A - A'

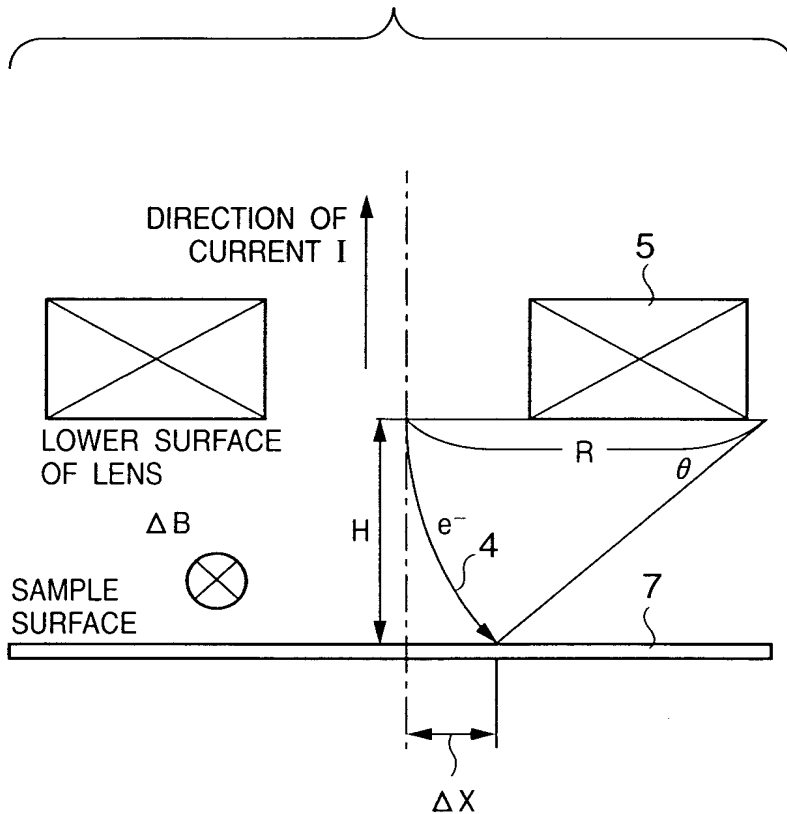
FIG. 3C



ENLARGED VIEW  
OF PORTION B

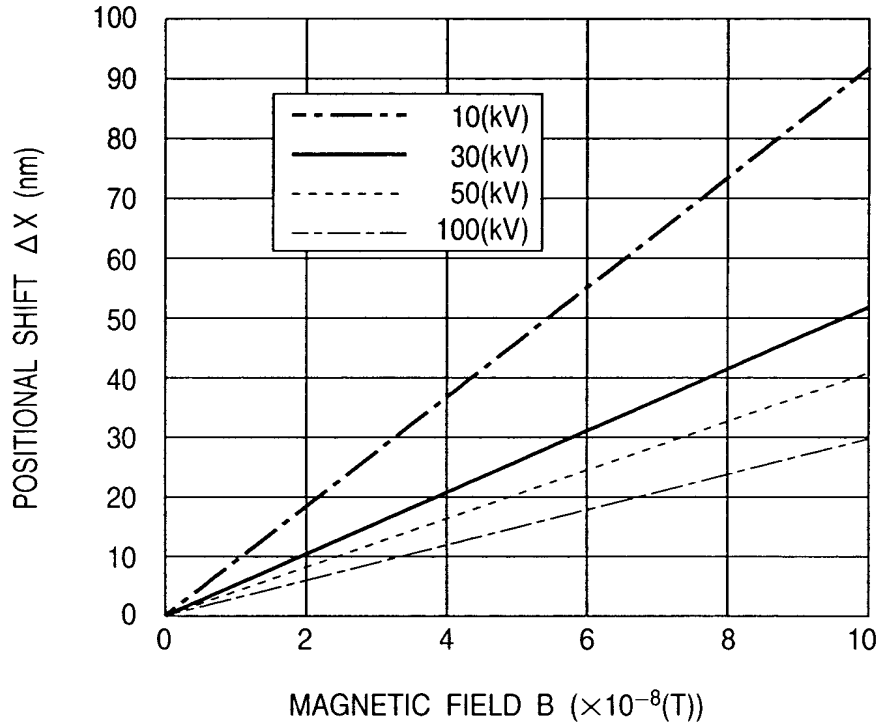
006707" 4E2T6960

FIG. 4



006101-4E2F6960

# FIG. 5



RELATIONSHIP BETWEEN POSITIONAL SHIFT OF ELECTRON BEAM AND MAGNETIC FIELD CHANGE AMOUNT (H=25(mm), E=10,30,50,100(kV))

006F01"4E2F6960

FIG. 6A

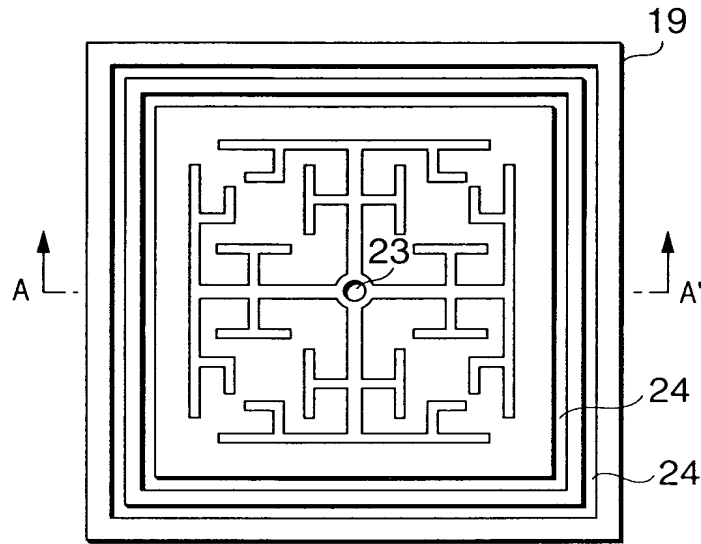
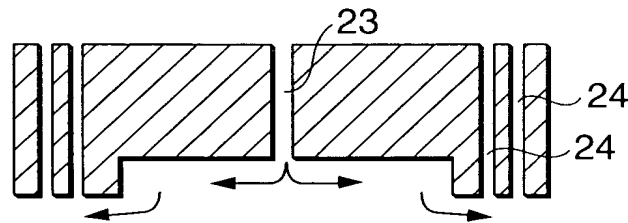


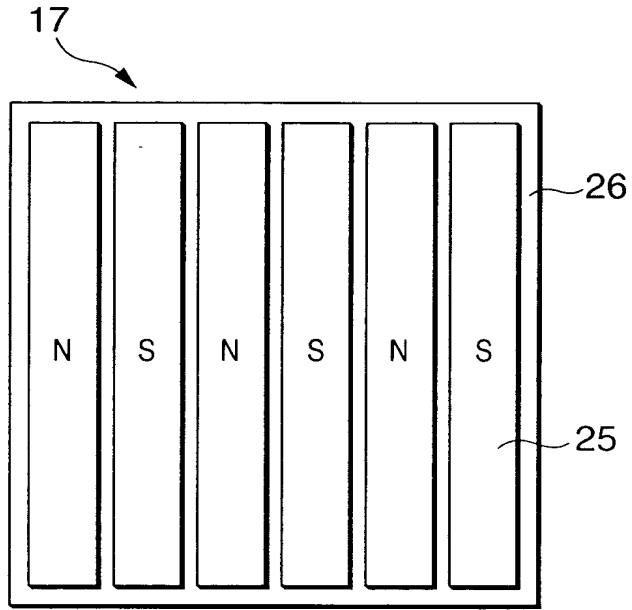
FIG. 6B



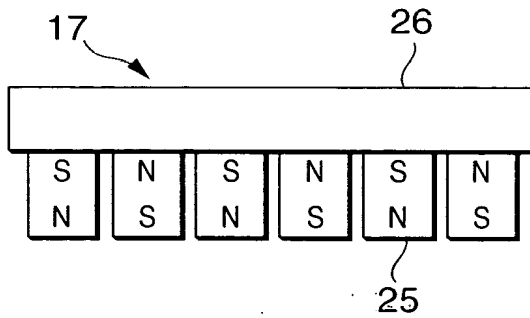
SECTIONAL VIEW TAKEN ALONG LINE A - A'

006T0T"4E2T6960

**FIG. 7A**

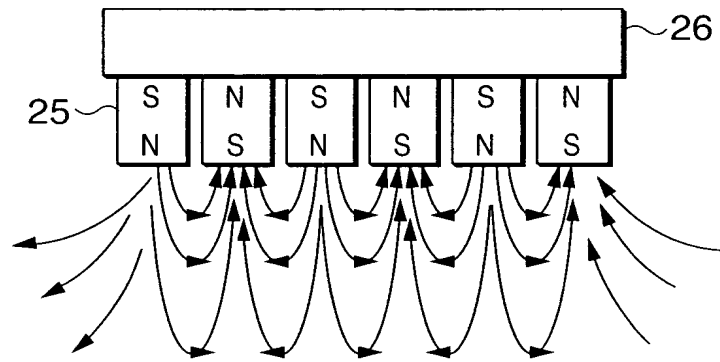


**FIG. 7B**



0969124-101900

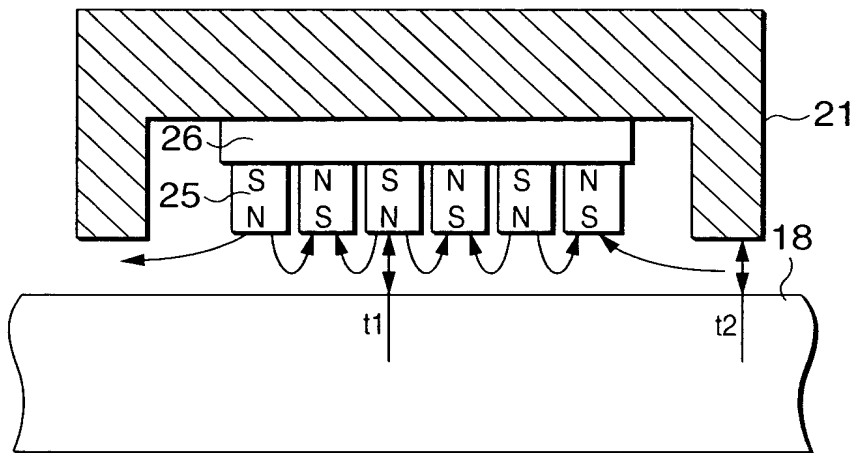
FIG. 8



006T0T" HE2T6960

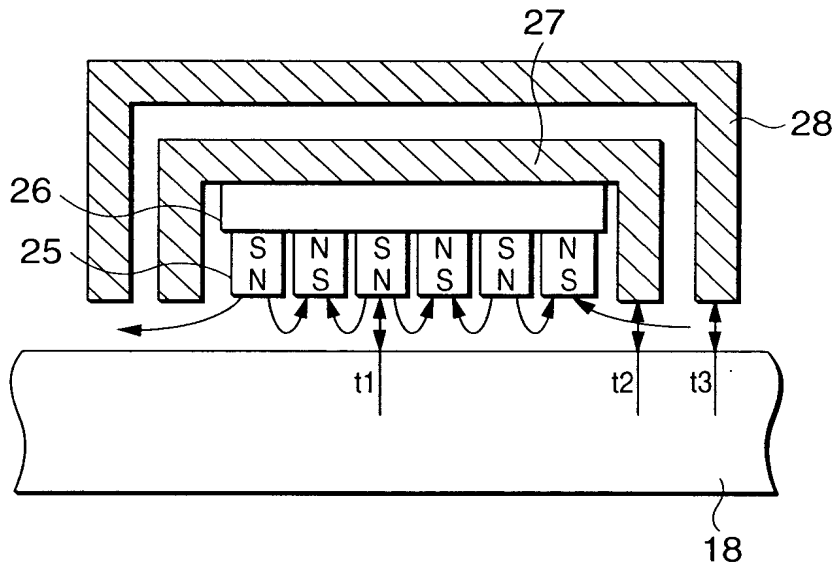


FIG. 9



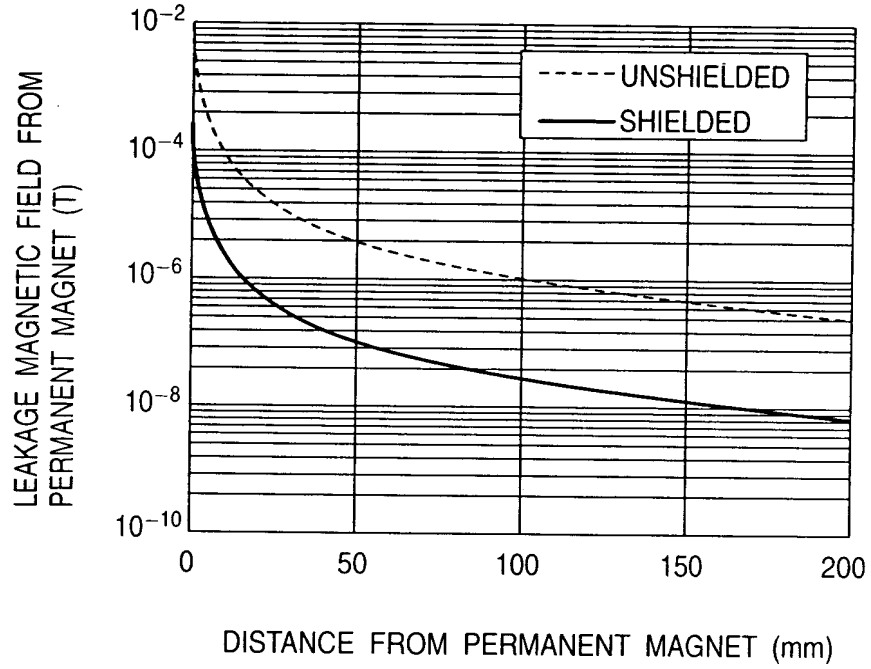
006707 "HE2T6360

FIG. 10



006 FOT. HE2T6960

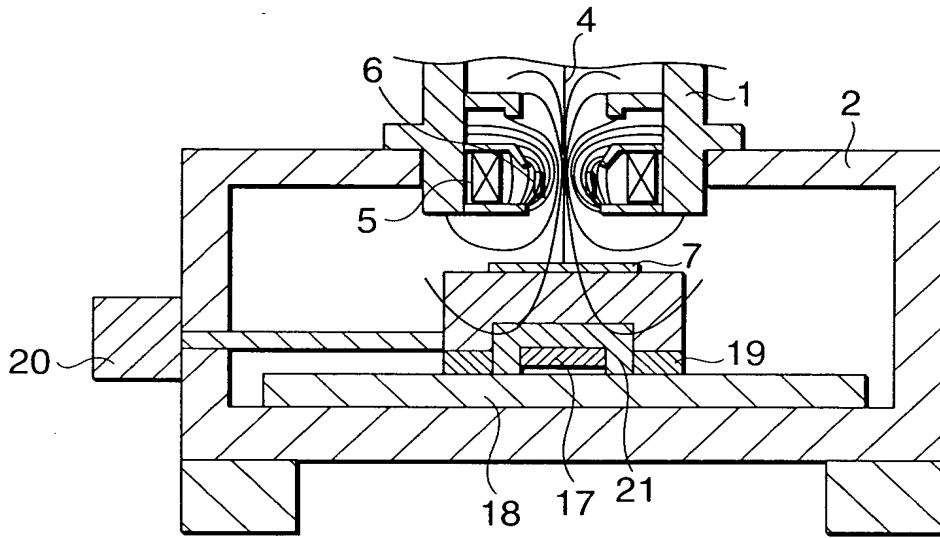
FIG. 11



EXTERNAL MAGNETIC FIELD SHIELD EFFECT OF PERMANENT MAGNET

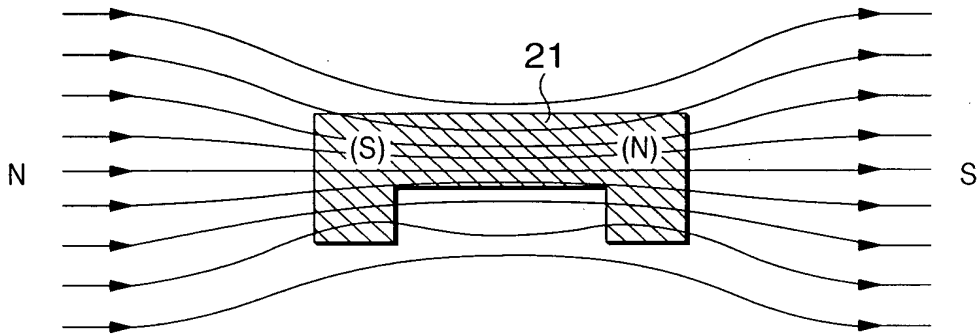
006707 14276960

FIG. 12



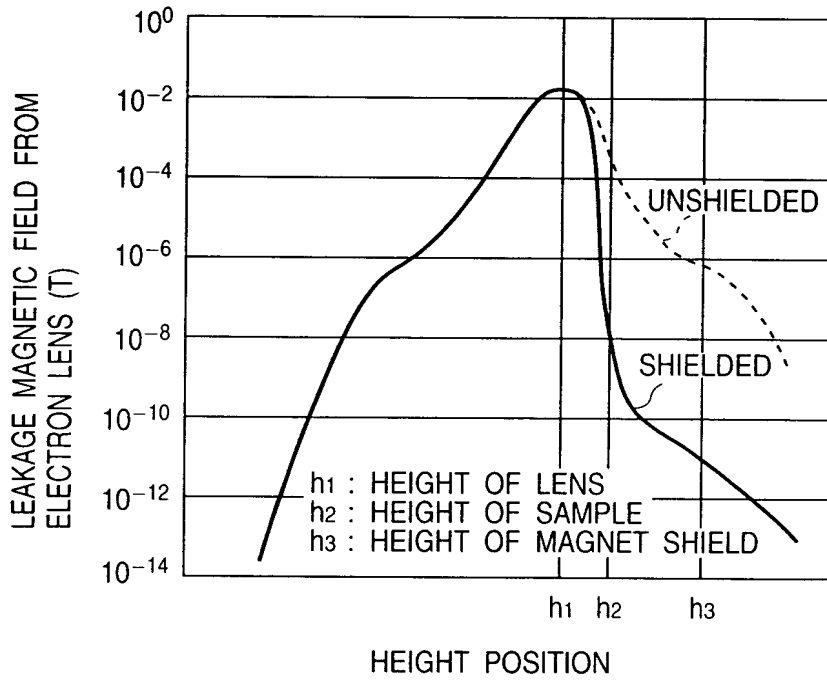
006707-16216963

FIG. 13



006T01" 4E2F6960

FIG. 14



SHIELD EFFECT FOR ELECTRON LENS LEAKAGE MAGNETIC FIELD

006FDI-HE2F6960

FIG. 15

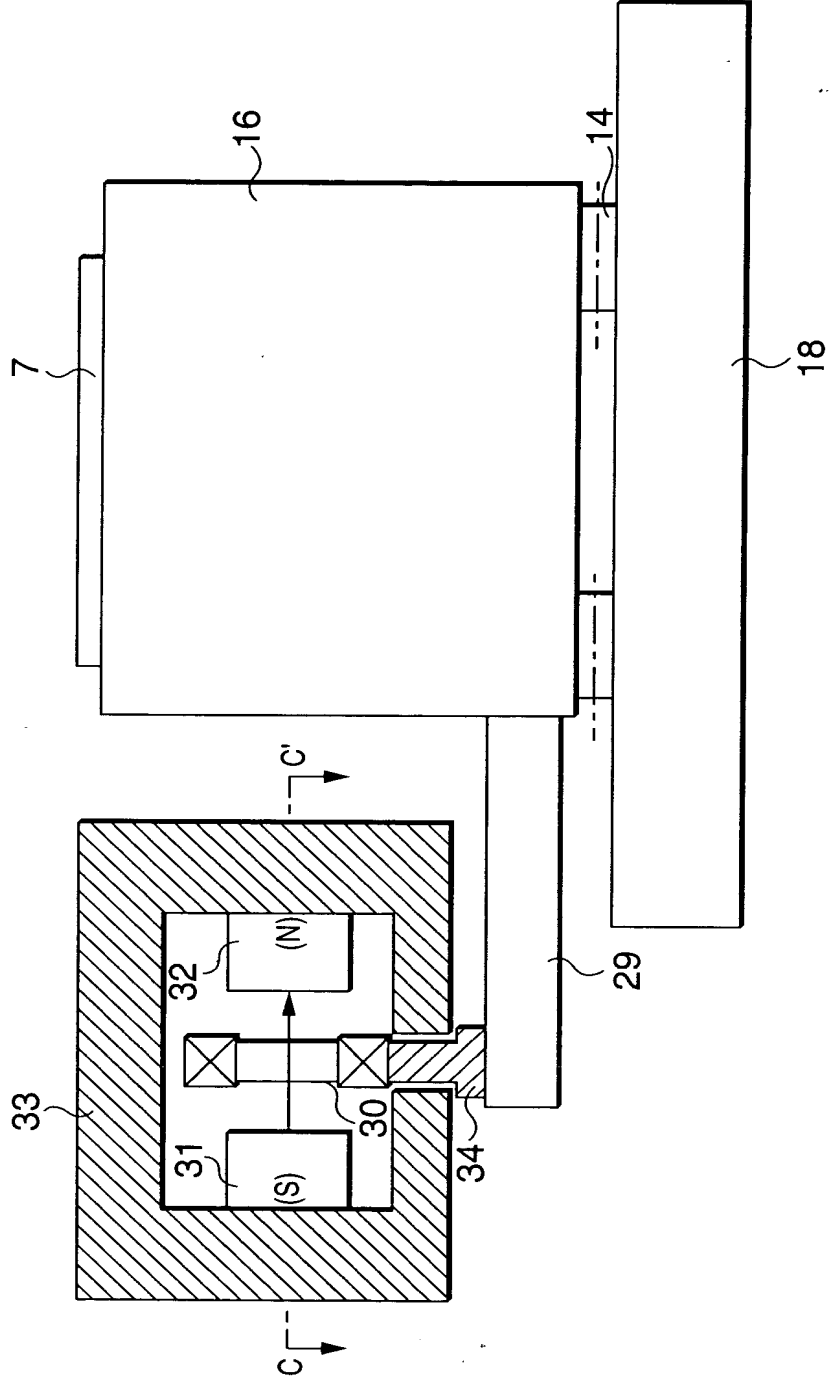
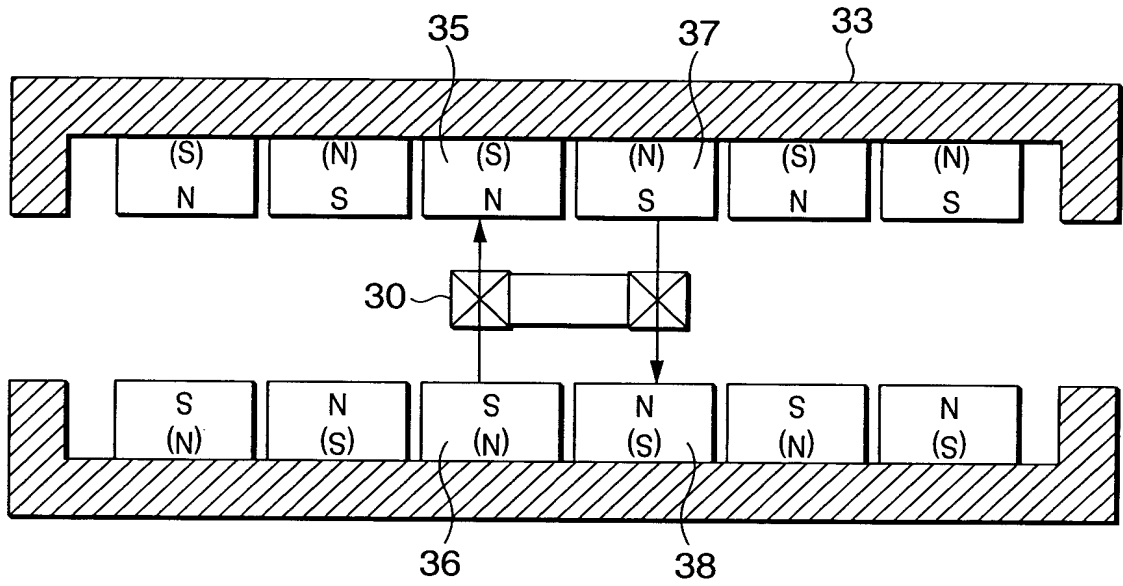


FIG. 16



CROSS-SECTIONAL VIEW TAKEN ALONG LINE C - C'

005101-42215950



FIG. 17

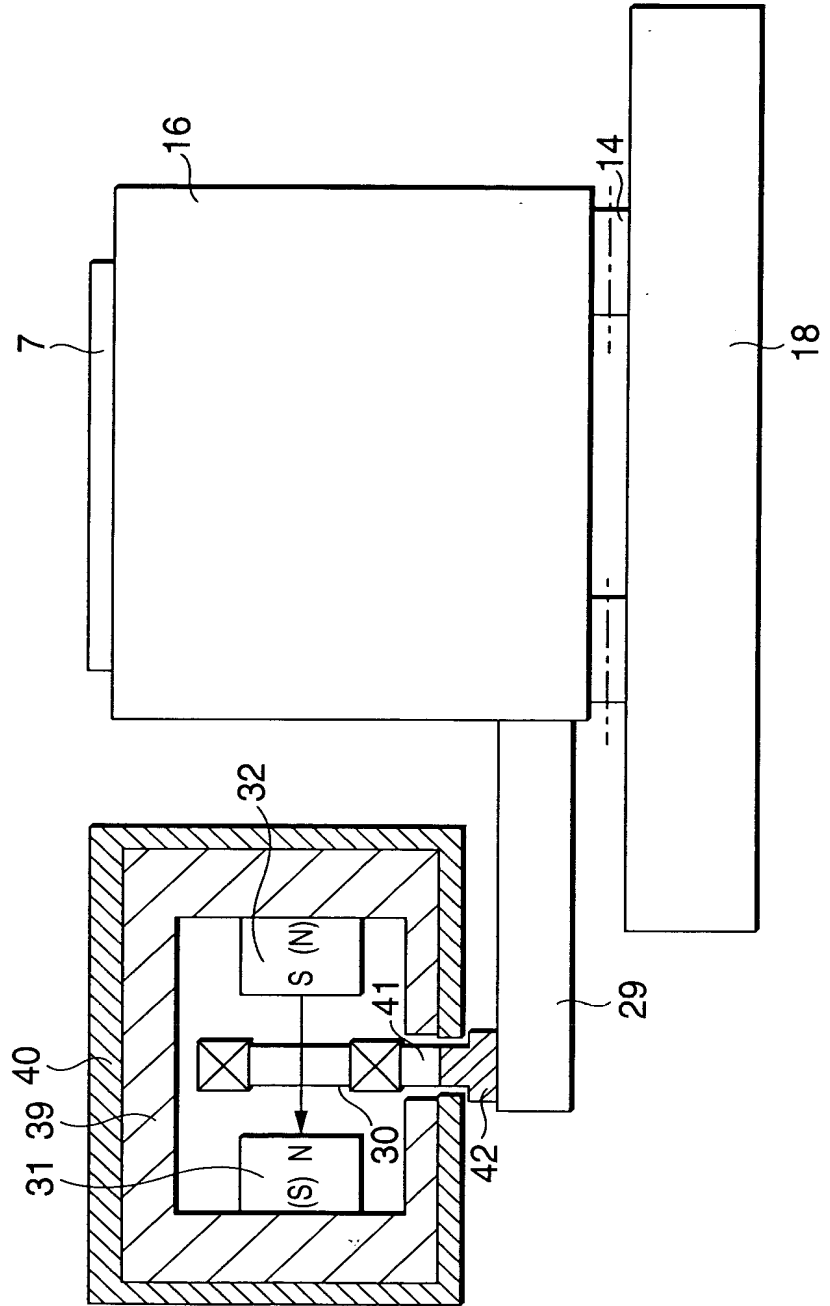


FIG. 18

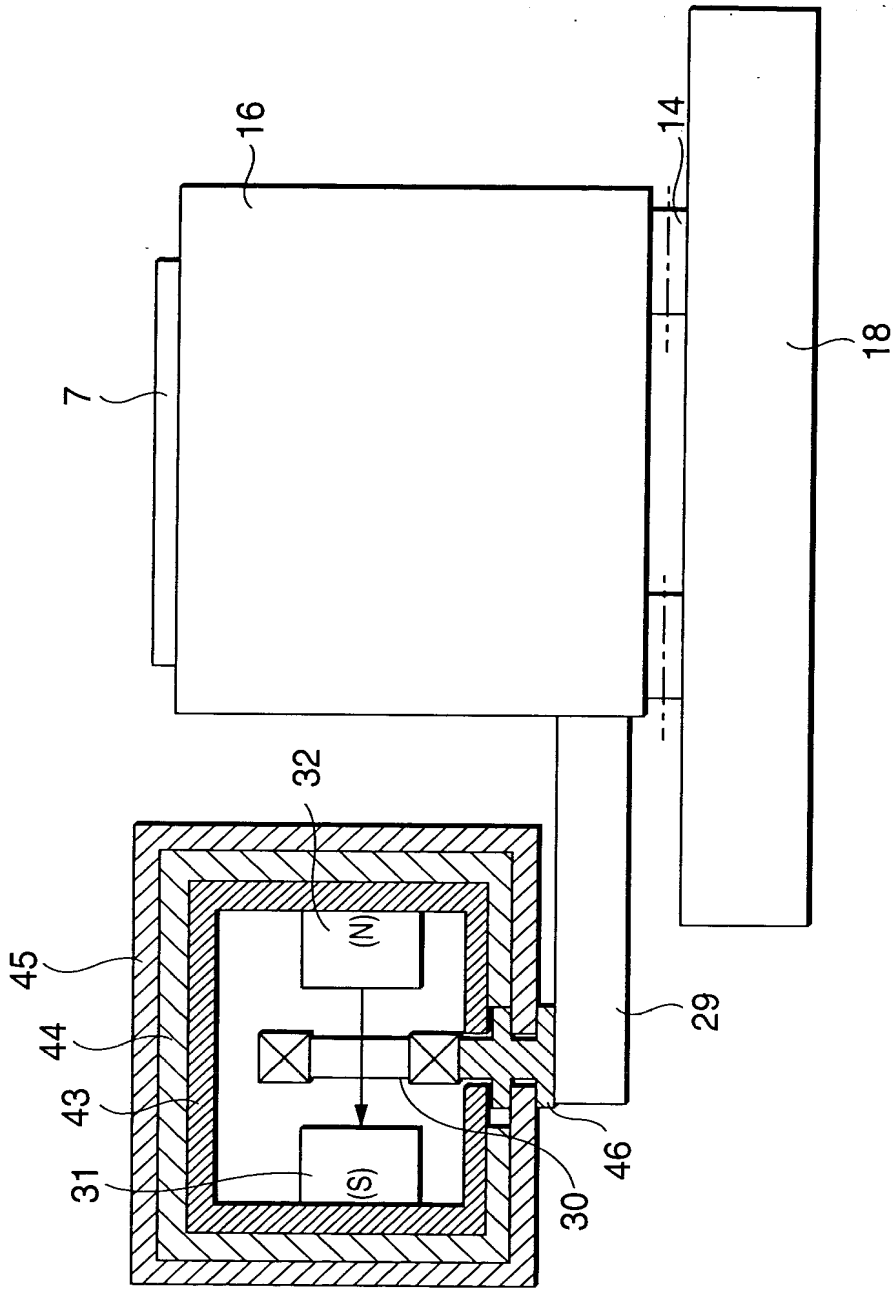


FIG. 19

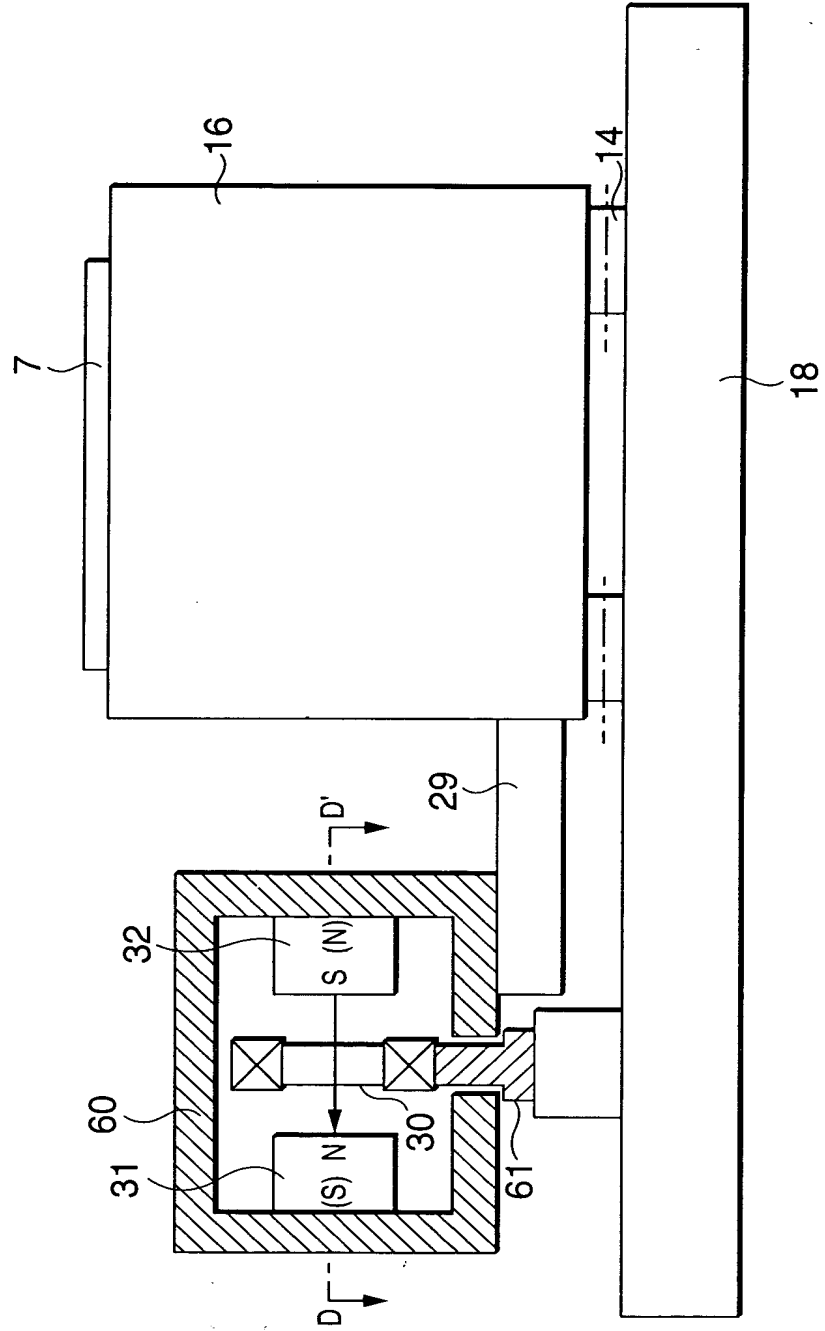
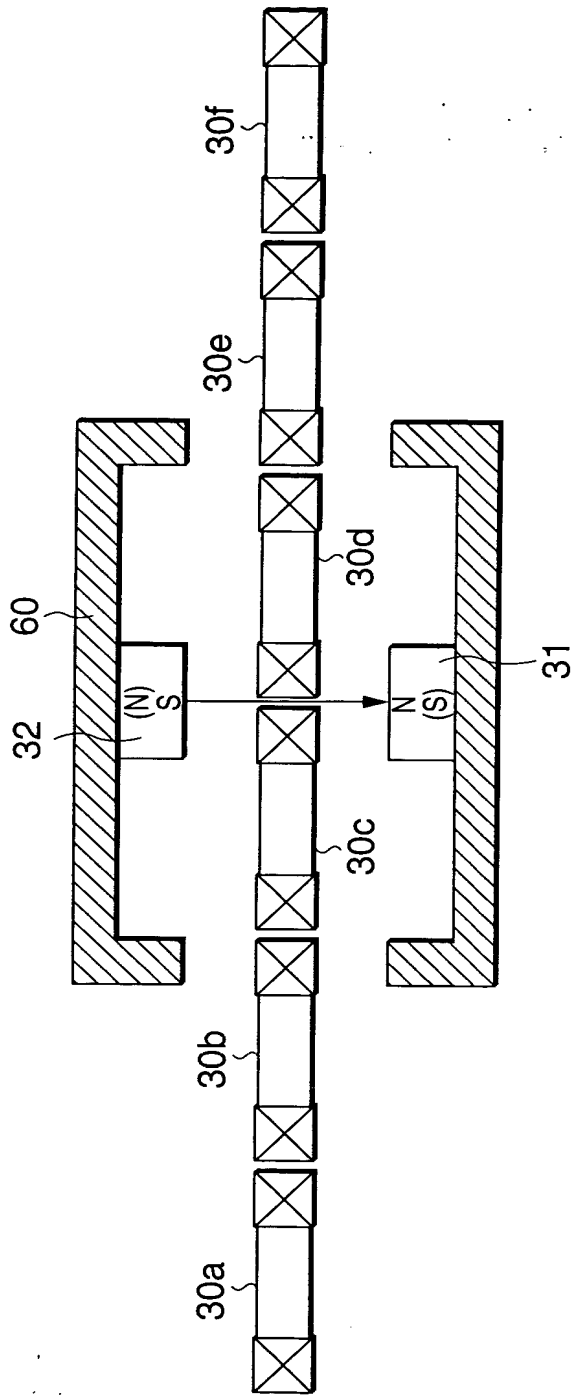


FIG. 20



CROSS-SECTIONAL VIEW TAKEN ALONG LINE D - D'

FIG. 21A

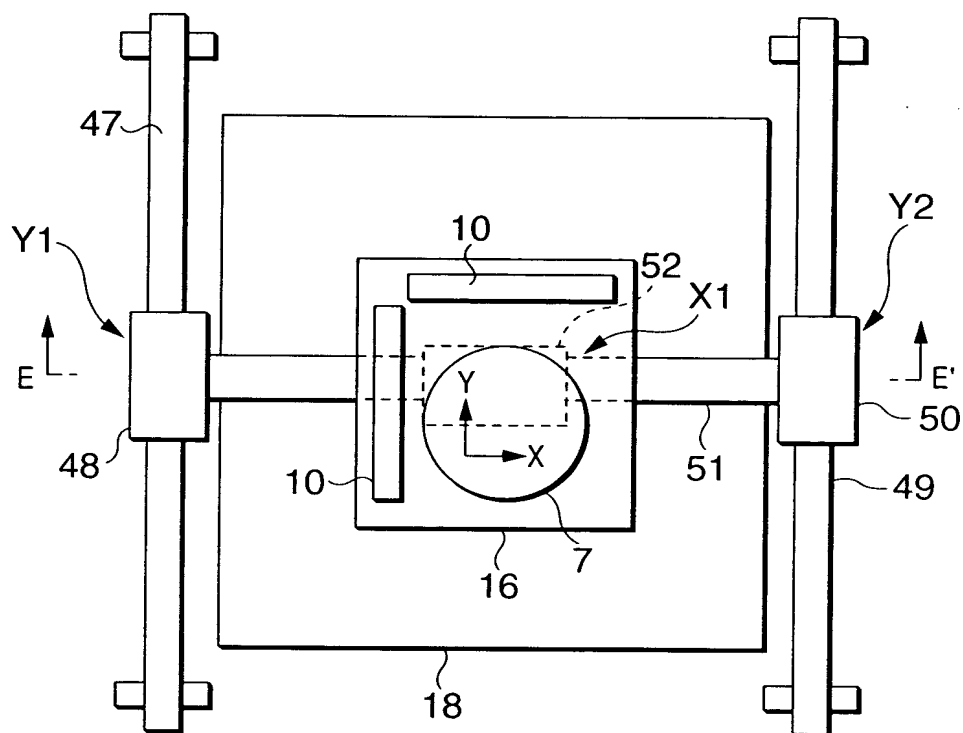
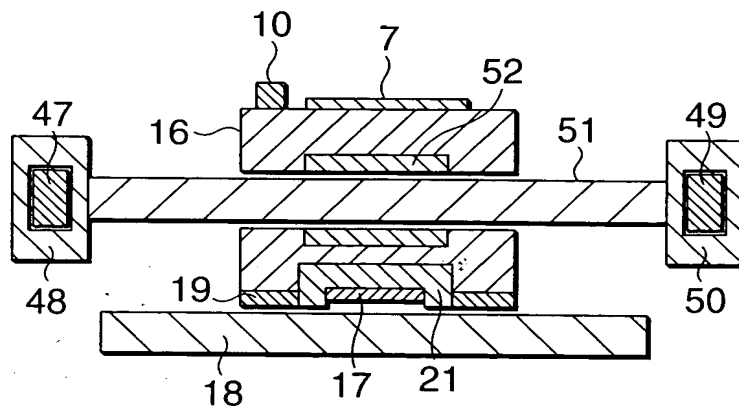


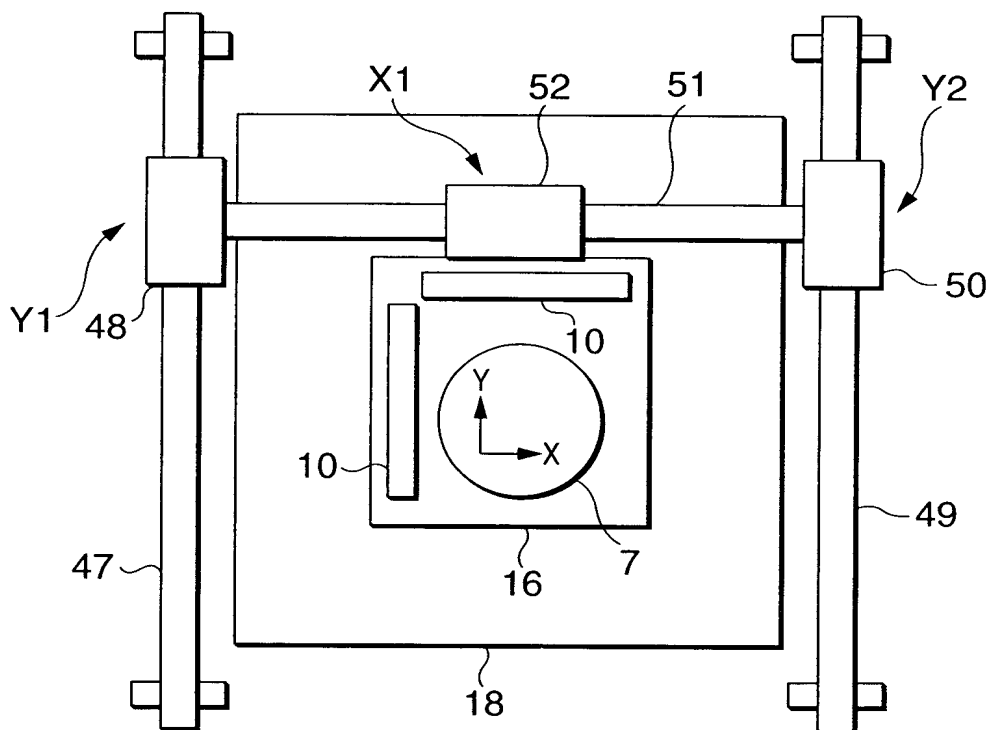
FIG. 21B



SECTIONAL VIEW TAKEN ALONG LINE E - E'

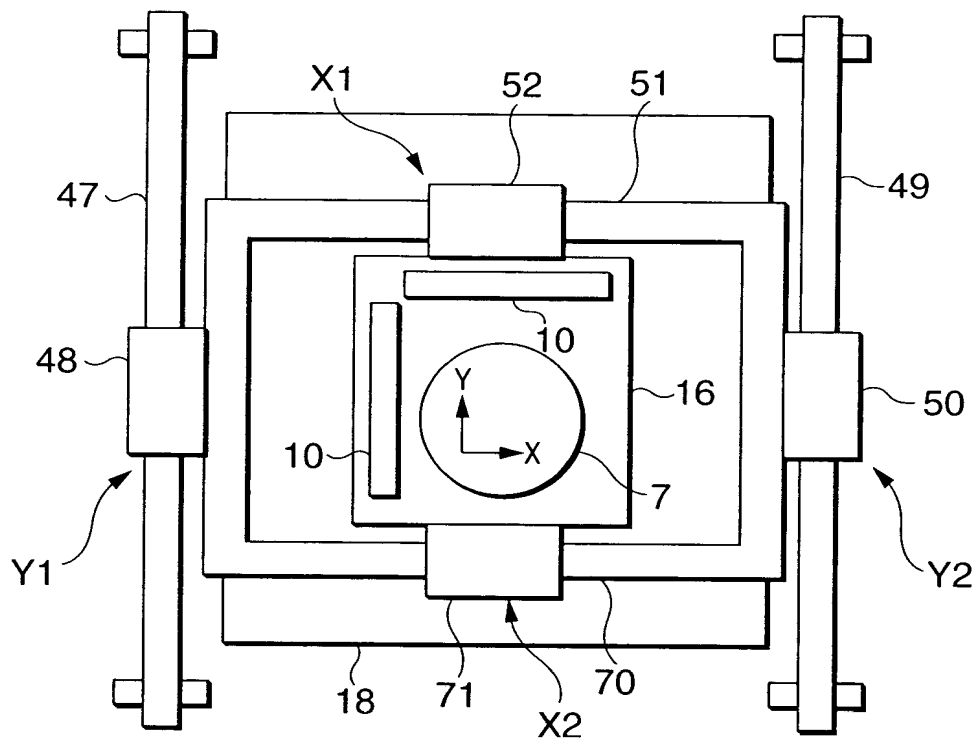
006F01-HE216960

FIG. 22



006101-4E2F6960

FIG. 23



006T01 "HEZFE960

FIG. 24A

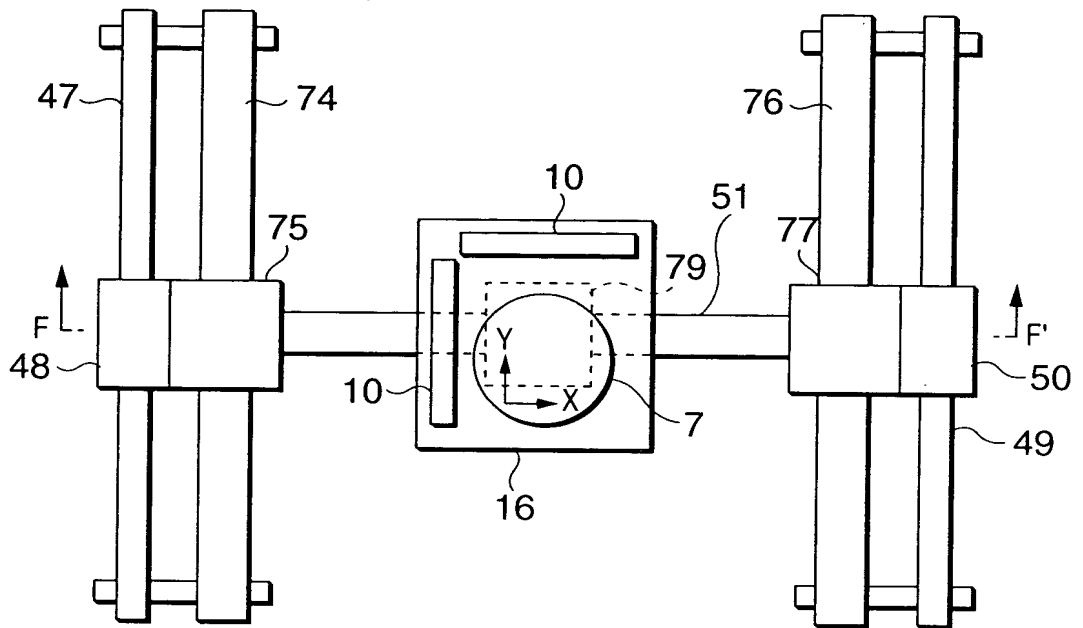
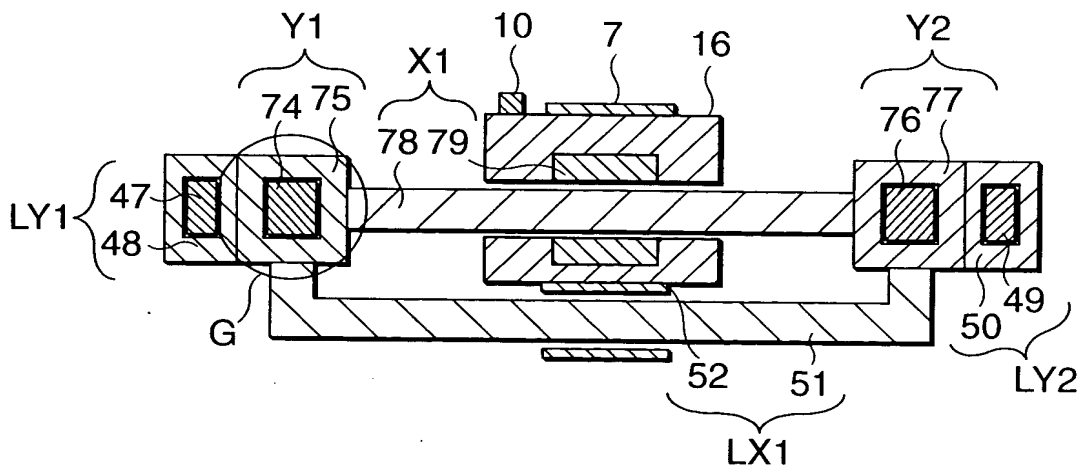


FIG. 24B

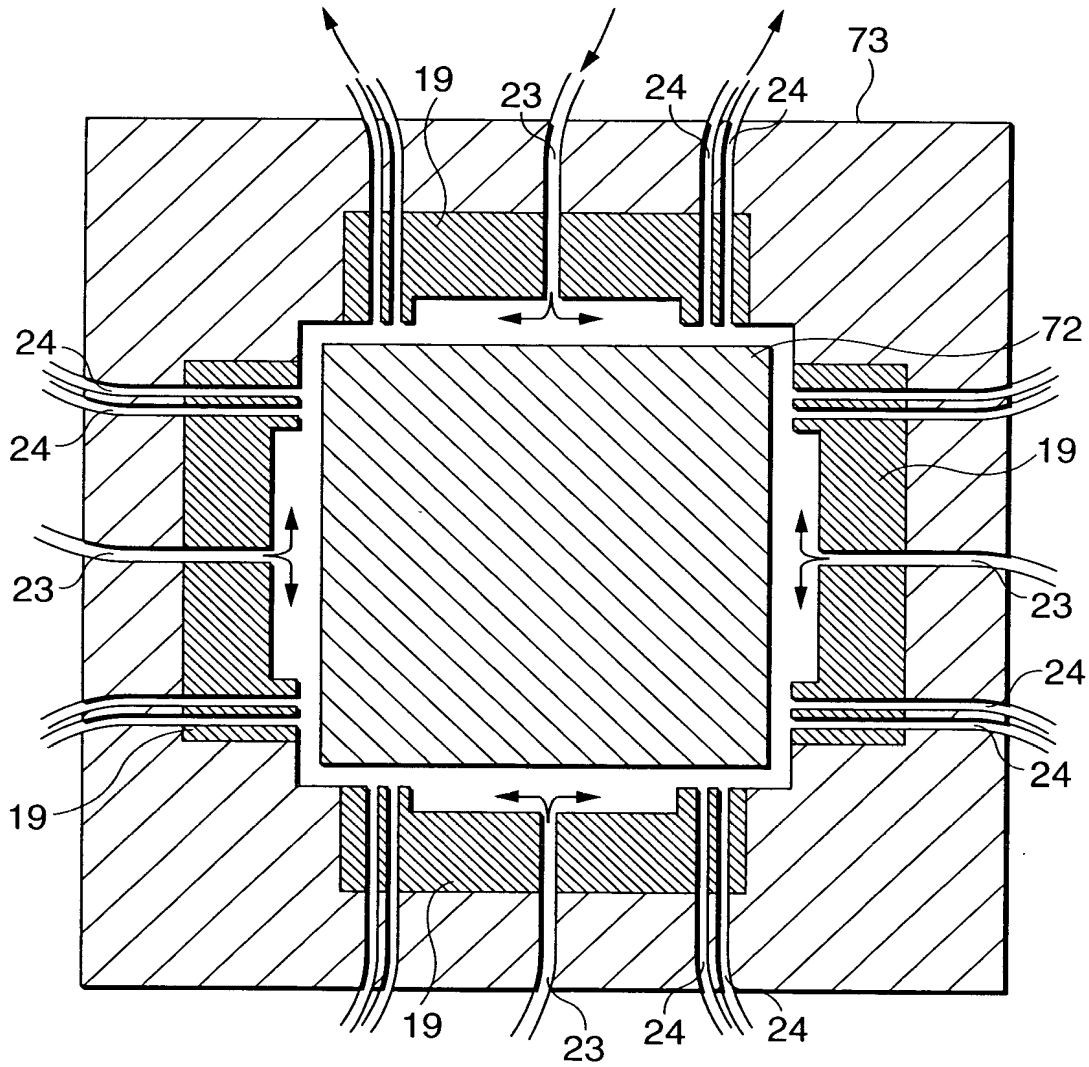


SECTIONAL VIEW TAKEN ALONG LINE F - F'

POSTNET TELETYPE



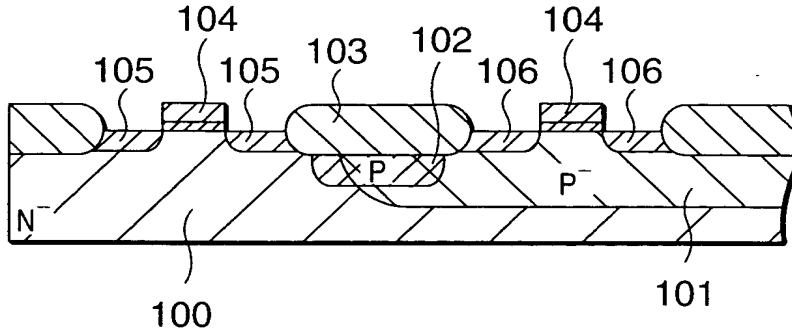
# FIG. 25



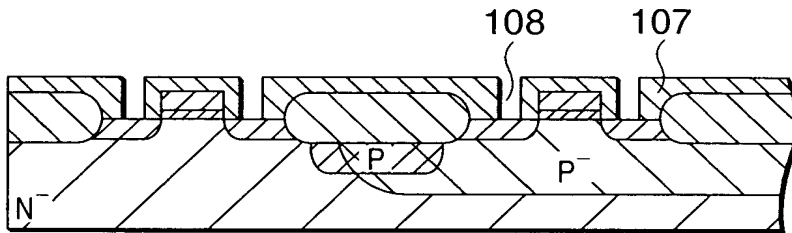
ENLARGED VIEW OF PORTION G IN FIG.24B

006101-14216960

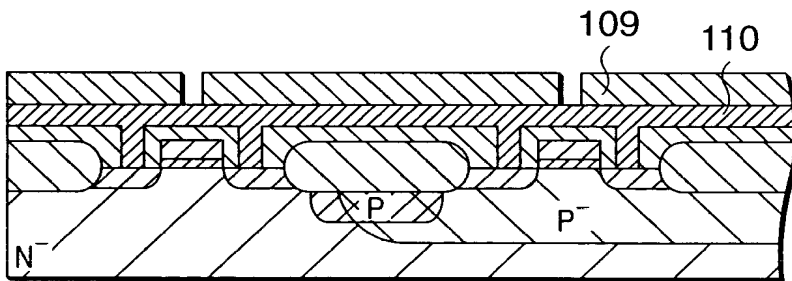
**FIG. 26A**



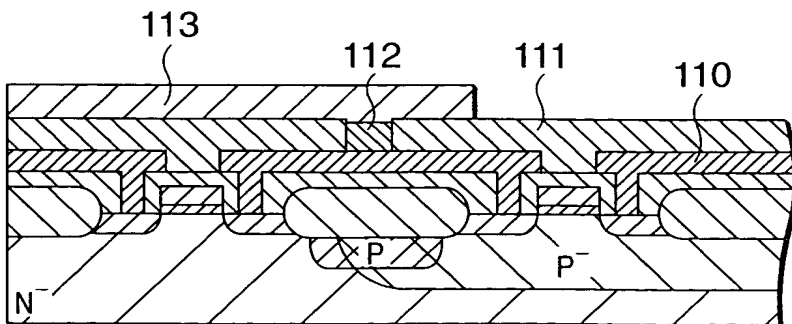
**FIG. 26B**



**FIG. 26C**



**FIG. 26D**



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